查询"2SK3935**†供x轴商**A Field Effect Transistor Silicon N-Channel MOS Type (π-MOSVI)

# 2SK3935

#### **Switching Regulator Applications**

• Low drain-source ON resistance  $: RDS (ON) = 0.18 \Omega$  (typ.)

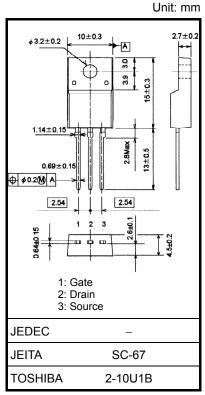
• High forward transfer admittance  $: |Y_{fs}| = 10 \text{ S (typ.)}$ • Low leakage current  $: I_{DSS} = 100 \mu\text{A (max) (V}_{DS} = 450 \text{ V)}$ 

• Enhancement model :  $V_{th} = 2.0 \text{ to } 4.0 \text{ V}$ 

 $(V_{DS} = 10 \text{ V}, I_{D} = 1 \text{ mA})$ 

#### Absolute Maximum Ratings (Ta = 25°C)

Characteri	stic	Symbol	Rating	Unit	
Drain-source voltage		$V_{DSS}$	450	V	
Drain-gate voltage (R <sub>G</sub>	<sub>iS</sub> = 20 kΩ)	$V_{DGR}$	450	V	
Gate-source voltage		V <sub>GSS</sub>	±30	V	
Drain current	DC (Note 1)	ID	17	Α	
	Pulse(Note 1)	I <sub>DP</sub>	68	Α	
Drain power dissipation	1	P <sub>D</sub>	50	W	
Single pulse avalanche	e energy (Note 2)	E <sub>AS</sub>	918	mJ	
Avalanche current		I <sub>AR</sub>	17	Α	
Repetitive avalanche e	nergy (Note 3)	E <sub>AR</sub>	5	mJ	
Channel temperature		T <sub>ch</sub>	150	°C	
Storage temperature ra	ange	T <sub>stg</sub>	-55~150	°C	



Weight: 1.7 g (typ.)

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

#### Thermal Characteristics

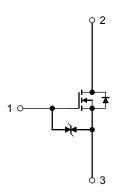
Characteristic	Symbol	Max	Unit
Thermal resistance, channel to case	R <sub>th (ch-c)</sub>	2.5	°C/W
Thermal resistance, channel to ambient	R <sub>th (ch-a)</sub>	62.5	°C/W

Note 1: Ensure that the channel temperature does not exceed 150°C during use of the device.

Note 2:  $V_{DD}$  = 90 V,  $T_{ch}$  = 25°C (initial), L = 5.3 mH,  $R_G$  = 25 $\Omega$ ,  $I_{AR}$  = 17 A

Note 3: Repetitive rating: pulse width limited by maximum channel temperature.

This transistor is an electrostatic-sensitive device. Handle with care.





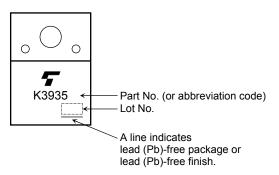
# Energy istics (Ta = 25°C)

Chara	cteristic	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cu	rrent	I <sub>GSS</sub>	V <sub>GS</sub> = ±25 V, V <sub>DS</sub> = 0 V	_	_	±10	μΑ
Drain-source bre	eakdown voltage	V (BR) GSS	$I_{G} = \pm 10  \mu A,  V_{GS} = 0  V$	±30	_	_	V
Drain cutoff curre	ent	I <sub>DSS</sub>	V <sub>DS</sub> = 450 V, V <sub>GS</sub> = 0 V	l	_	100	μA
Drain-source bre	eakdown voltage	V (BR) DSS	I <sub>D</sub> = 10 mA, V <sub>GS</sub> = 0 V	450	_	1	V
Gate threshold v	roltage	$V_{th}$	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 1 mA	2.0	_	4.0	V
Drain-source ON	l resistance	R <sub>DS</sub> (ON)	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 8.5 A	_	0.18	0.25	Ω
Forward transfer	admittance	Y <sub>fs</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 8.5 A	2.5	9.5	_	S
Input capacitance		C <sub>iss</sub>	V <sub>DS</sub> = 25 V, V <sub>GS</sub> = 0 V, f = 1 MHz	_	3100	_	pF
Reverse transfer capacitance		C <sub>rss</sub>		_	20	_	
Output capacitance		Coss		_	270	_	
Switching time	Rise time	t <sub>r</sub>	10 V VGS 0 V VDD≈ 200 V	_	70	_	
	Turn-on time	t <sub>on</sub>		_	130	_	ns
	Fall time	t <sub>f</sub>		_	70	_	. 115
	Turn-off time	t <sub>off</sub>	Duty ≤ 1%, t <sub>w</sub> = 10 μs		280		
Total gate charge (gate-source plus gate-drain)		$Q_{g}$	V <sub>DD</sub> ≈ 360 V, V <sub>GS</sub> = 10 V, I <sub>D</sub> = 17 A	_	62	_	
Gate-source charge		Q <sub>gs</sub>		_	40	_	nC
Gate-drain ("Miller") charge		$Q_{gd}$		_	22	_	

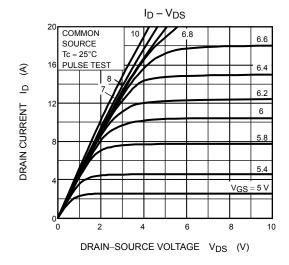
## Source-Drain Ratings and Characteristics (Ta = 25°C)

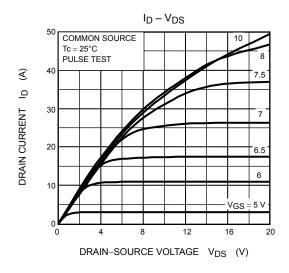
Characteristic	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I <sub>DR</sub>	_	_	_	17	Α
Pulse drain reverse current (Note 1)	I <sub>DRP</sub>	_	_	_	68	Α
Forward voltage (diode)	V <sub>DSF</sub>	I <sub>DR</sub> = 17 A, V <sub>GS</sub> = 0 V	_	_	-1.7	V
Reverse recovery time	t <sub>rr</sub>	I <sub>DR</sub> = 17 A, V <sub>GS</sub> = 0 V	_	1400	_	ns
Reverse recovery charge	Qrr	$dI_{DR}$ / $dt = 100 \text{ A}$ / $\mu$ S	1	21	_	μС

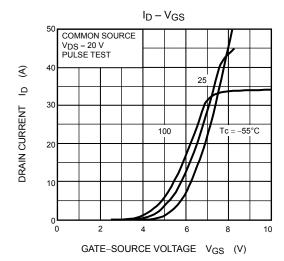
### Marking

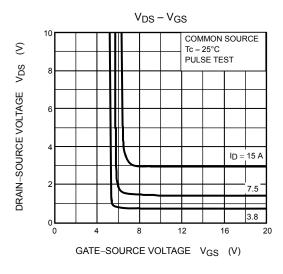


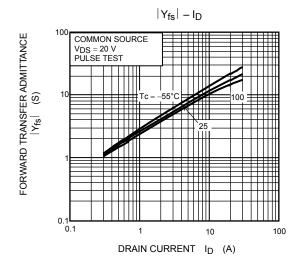
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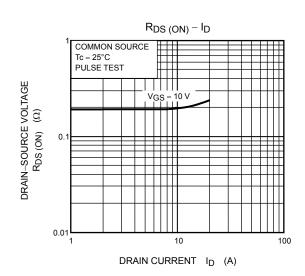


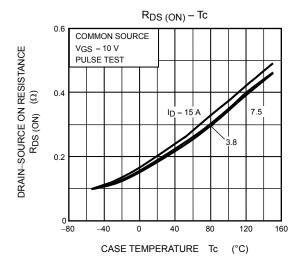


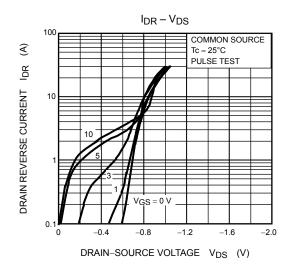


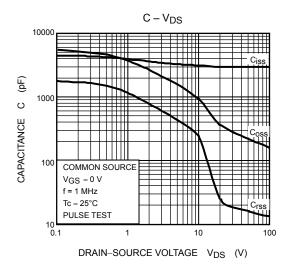


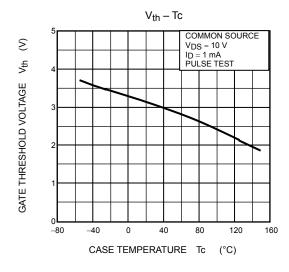


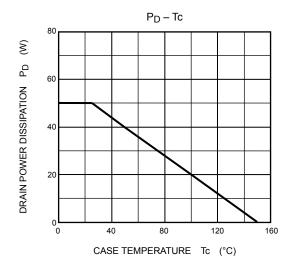


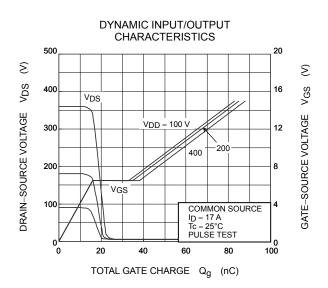


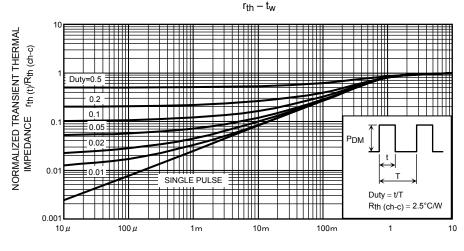




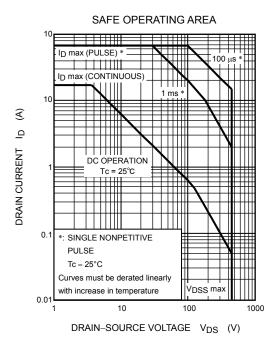


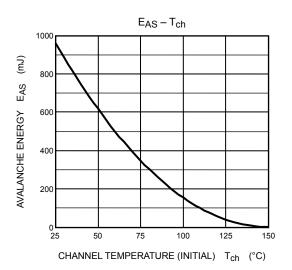


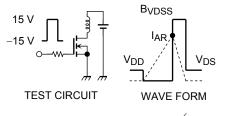




PULSE WIDTH  $t_W$  (s)







$$\begin{aligned} R_G &= 25~\Omega \\ V_{DD} &= 90~V,~L = 5.3~mH \end{aligned}$$

$$EAS = \frac{1}{2} \cdot L \cdot I^2 \cdot \left( \frac{BVDSS}{BVDSS - VDD} \right)$$

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